

QUERY CONTROL FORM		RTIS USE ONLY	
Application No.	101020,208	Prepared by	NH
Examiner-GAU	Auduong-2818	Date	2-17-4
		No. of queries	IFW
		Tracking Number	05894361
		Week Date	01/26/04

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE	
a. Page Missing	<p>PTO-1449: Please either initial or line through citations. Copy provided for reference.</p>	
b. Text Continuity		
c. Holes through Data		
d. Other Missing Text		
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g. Brief Description		
h. Sequence Listing		
i. Appendix		
j. Amendments		
k. Other		
CLAIMS		
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d. Incorrect Numbering		
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APPLICATION NO./ CONTROL NO.	FILING DATE	FIRST NAMED INVENTOR / PATENT IN REEXAMINATION	ATTORNEY DOCKET NO.
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EXAMINER

ART UNIT	PAPER
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031504

DATE MAILED:

Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner for Patents


Attached is the PTO-1449 that initial to consider the cited references that missing from previous mailed.

Gene N Auduong
Primary Examiner
Art Unit: 2818



Electronic Information Disclosure Statement











System and Method to Screen Defect Related Reliability Failures in CMOS SRMAS

Application: 
10/020208
Confirmation: 7966
Applicant(s): Surya Bhattacharya
Docket Number: 1875.0330001
Group Art Unit: 2818
Examiner:
search string: (5745415 or 5661729 or 6154403 or 6115304 or 6081464 or 6038189).on

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US Patent Documents



Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Citation No.	Patent Number	Date	Bar Code	Patentee	Class	Subclass
	P01	5745415	1998-04-28		Marr	365	201
	P02	5661729	1997-08-26		Miyazaki et al.	714	719
	P03	6154403	2000-11-28		Tanzawa et al.	365	203
	P04	6115304	2000-09-05		Suga	365	201
	P05	6081464	2000-06-		Marr	365	201


APP_ID=10020208

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			27		
	P06	6038181	2000-03-14		Braceras et al. 365/201

Signature

Examiner Name	Date
	5/03